MPI T53000–5E 300 mm Automated Probe System with ShielDEnvironment[™]

The Dedicated Solution for ultra-low noise IV, CV, pulsed-IV, 1/f and RF Measurements

Microscope and Optics Options

- Stable microscope bridge mount with 50 x 50 x 140 mm programmable movement
- Various optics options available such as MPI AMZ12 w. up to 12x optical zoom or MPI iMAG[®] - the digital microscope

MicroPositioners and High Power Probes

- Supports up to 4 RF and 8 DC MicroPositioners
- Wide range of MicroPositioners available, including large area for mmW applications
- Dedicated Coax, Triax and Kelvin probe arms

Probe Platen

- Stable and rigid design
- Rectangular adjustments for RF positioners
- Integrated air-cooling for maximum thermal stability

ShielDEnvironment™

- Advanced EMI / RFI / Light-tight shielding for the best 1/f noise test results
- fA low-leakage capabilities

Integrated Vibration Isolation Table

- Incorporates a high performance vibration isolation platform
- Optimal working height for ergonomic daily operation



Software Suite SENTIO

- Simple and intuitive system operation by revolutionary multi-touch control
- Scroll, Zoom, Move commands mimic modern smart mobile devices making everyone the operation expert just in minutes
- Switching between applications is just a matter of a finger swipe
- Integrated workflow with MPI RF calibration software QAlibria[®] provides unparalleled user experience
- GPIB, TCP/IP interface for remote control

RF Calibration

- Integrated two auxiliary chucks for RF calibration substrates
- Built-in ceramic for accurate calibration up to THz frequencies
- 1 µm flatness for consistent contact across the wafer

Thermal Chuck Integration

- Wide temperature range -60 °C to 300 °C with unique configuration capabilities
- Convenient location of the control pannel for fast and easy interaction with the system
- Reduced footprint by smart integration of the chiller space

Integrated Hardware Control Panel

- Provide faster, safer and more convenient system operation and control
- Keyboard and the mouse are at the system control panel for a single-point operation with the system and controlling test instrumentation

Available Options

 Optional instrument shelf reduces the length of RF cables providing the highest measurement dynamic range and improves system directivity.